



Retraction Note: Effect of target to substrate distance on the material properties of the $Y_2SiO_5:Ce^{3+}$ thin film by pulsed laser deposition

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Correction to: Applied Physics A (2019) 125:172
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The Editor-in-Chief has retracted this article. Following publication concerns were raised regarding data underlying Figs. 1 and 2. Specifically, the results presented in these figures may suggest that they were derived from a material other than the one named in the article. Additionally, the calculations of average crystallite size appear to be incorrect, which may have led to a significantly different outcome. Post-publication peer review has confirmed these concerns.

The Editor-in-Chief therefore no longer has confidence in the results and conclusions of this article.

Author H. T. Haile does not agree to this retraction. Author F. B. Dejene has not responded to any correspondence from the editor or publisher about this retraction.

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The original article can be found online at <https://doi.org/10.1007/s00339-019-2473-4>.

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